REPORT DOCUMENTATION PAGE	Form Approved OMB No. 0704-0188		
Public reporting burden for this collection of information is estimated to average 1 hour per response, including the time for review maintaining the data needed, and completing and reviewing the collection of information. Send comments regarding this burden including suggestions for reducing this burden, to Washington Headquarters Services, Directorate for information Operations and VA 22202-4302, and to the Office of Management and Budget, Paperwork Reduction Project (0704-0185), Washington, DC 205	ving instructions, searching existing data sources, gathering and selimate or any other aspect of this collection of information, I Reports, 1216 Jefferson Davis Highway, Suite 1204, Arington, 03,		
1. AGENCY USE ONLY (Leave Blank) 2. REPORT DATE 3. REPORT TYP	3. REPORT TYPE AND DATES COVERED		
12/12/1994 interim	interim olNov-OlDec 1994		
4. TITLE AND SUBTITLE A New Growth Technology for Hig Non-Linear Optical Quality Organic Films: Organic Vapor Phase Deposition	Th Ey NOO014-94-C-0168		
6. AUTHOR(8) Dr. V.S. Ban			
7. PERFORMING ORGANIZATION NAME(S) AND ADDRESS(ES) PD-LD, Inc. 209 Wall Street	8. PERFORMING ORGANIZATION REPORT NUMBER		
Princeton, NJ 08540	0004		
9. SPONSORING/MONITORING AGENCY NAME(S) AND ADDRESS(ES) Dr. John Pazik, Office of Naval Res. code 251 ALMW	10. SPONSORING/MONITORING AGENCY REPORT NUMBER		
Ballston Tower One- 800 N. Quincy St. Arlington VA 22217-566	o DTIC		
11. SUPPLEMENTARY NOTES	DEC 2 8 1994		
12a. DISTRIBUTION/AVAILABILITY STATEMENT	12b. DISTRIBUTION CODE		
This document has been approved for emblic release and sale; its of loomion is unlimited.	Community or any		
13. ABSTRACT (Meximum 200 words)			

NMR spectroscopy identified the main impurity in DAST films grown by OVPD method. The impurity is a trimethilated compound described in last month report. Thus our films consist of over 90 % DAST and some 5 to 10 % of the above impurity.

An apparatus for measuring second harmonic generation properties of OVPD DAST films has been constructed and described. We expect to do quantitative measurements this month.

We continue the optimization of growth conditions of the OVPD method This month we shall grow from tosylate starved atmosphere and study effects of substrate nature on optical properties of grown films.

14. BUBJECT TERMS			15. NUMBER OF PAGES
non-linear mater DAST			16. PRICE CODE
Organic Vapor Pb. 17. SECURITY CLASSIFICATION OF REPORT	ase Deposition 18. SECURITY CLASSIFICATION OF THIS PAGE	19. SECURITY CLASSIFICATION OF ABSTRACT	20. LIMITATION OF ABSTRACT
unclassified	unclassified		

NBN 7540-01-280-5800

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Standard Form 298 (Rev. 2-89) PN softed by ANSI Std. 299-18 298-102

PROGRESS REPORT #4

Contract No. N00014-94-C-0168 Scientific Officer: Dr. John Pazik, ONR

Scientific Officer: Dr. John Pazik, ONK Period covered: 01 Nov1994 - 01 Dec1994

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Title: A New Growth Technology For Highly Non-Linear, Optical Quality Organic Films: Organic Vapor Phase Deposition

Work performed:

1. NMR analysis of DAST films;

In the last month report we described the plan to elucidate the nature of the by-product detected in the NMR analysis of DAST films grown by the OVPD method. The analysis has shown that the main by-product is the trimethilathed species,[structure A in the Progress report No.3]. Thus, the OVPD grown films consist of at least 90% DAST and 5-10 % of the above by-product. The analytical results will be described in more details in the next months report.

2. Growth experiments

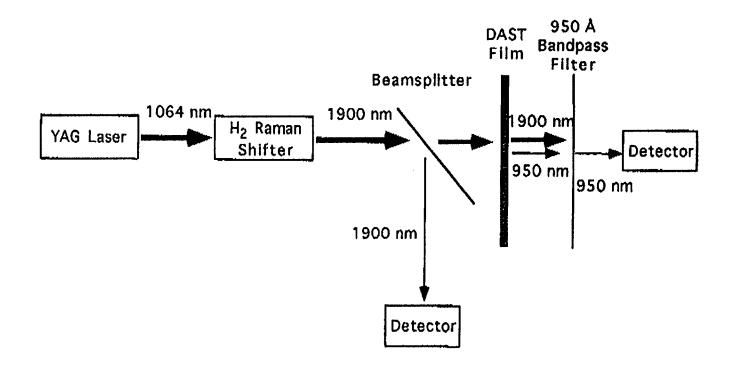
We are continuing optimization of the growth conditions. In view of the analytical results, we are concentrating on growth of films with less tosylate rich growth atmosphere. The other approach is to grow films on substrates other than glass slides, in order to ascertain the effect of the nature of the substrate on the optical quality of films.

3. Second Harmonic Generation experiments

We have observed second harmonic generation, [SHG], of green light from 1064 A infrared fundamental. Qualitatively, the intensity of green light is of the same order as that observed from crystals of pure DAST obtained from JPL. Encouraged by this result, we have set out to quantify the second harmonic generation efficiency of the OVPD grown films. Since DAST strongly absorbs green light, it is difficult to perform a quantitative measurements using 1064/532 nm light. By building an H2 Raman shifter, we are able to perform a direct χ^2 measurements using 1900/950 nm light, neither of which is strongly absorbed by DAST. The optical system illustrated, [see figure], has been completed and will now enable us to quantitavely asses the χ^2 efficiency of our films compared to pure DAST. This analysis will enable us to optimize the film growth for SHG applications.

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Apparatus for measurement SHG activity of DAST films grown by the OVPD method